



SHEET 1 OF 1

INFORMATION DISCLOSURE CITATION PTO-1449				ATTY. DOCKET NO. SUN04-0554-EKL		APPLICATION NO. 10/713,847	
				APPLICANT Hideya Kawahara, et al.			
				FILING DATE November 14, 2003		GROUP ART UNIT 2671	
U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
PV	US2004/0090467 A1	May 13, 2004	Bonura et al.	345	790	11/5/03	
FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER P. Nguyen				DATE CONSIDERED 6/12/05			

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



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U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
PN	2002/0113820	Aug. 22, 2002	Robinson et al.	345	764	12/20/00	
	2001/0040571	Nov. 15, 2001	Miller	345	419	11/15/01	
	6,229,542	May 8, 2001	Miller	345	358	7/10/98	
PN	5,880,733	Mar. 9, 1999	Horvitz et al.	345	355	3/9/99	
FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT OR PUBLICATION NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
PN	WO 00/60442	12 October 2000	PCT	G06F	3/033		
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc)							
EXAMINER P. Nguyen				DATE CONSIDERED 6/12/06			

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U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
PV	5,831,617	Nov. 3, 1998	Bhukhanwala	345	349	11/22/96	
FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT OR PUBLICATION NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
PV	04/044727	27 May 2004	PCT	G06F-3/033	H04M-1/247		
PV	02/33568	25 April 2002	PCT	G06F-15/177	15/173		
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER P. Nguyen				DATE CONSIDERED 6/12/06			

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U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
PV	5,601,432	11 Feb 1997	Bergman	434	118	20 Jan 95	
PV	5,689,286	18 Nov 1997	Wugofski	345	348	1 Jul 96	
FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT OR PUBLICATION NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
PV	WO 02/029760	11 April 2002	PCT	G06F	17/30		
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER P. Nguyen				DATE CONSIDERED 6/12/06			

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